

**LIST OF REFERENCES CITED BY APPLICANT**  
(Use several sheets if necessary)

ATTY DOCKET NO.

060937-0178

APPLICATION NO

10/802,780

APPLICANT

Robert J. SMALL

FILING DATE

march 18, 2004

GROUP

1792

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/MLP/	A01	3,848,258	11/1974	Mahoney et al.			
	A02	3,893,131	07/1975	Perel et al.			
	A03	4,124,801	11/1978	Cook et al.			
	A04	4,264,641	04/1981	Mahoney et al.			
	A05	4,318,028	03/1982	Perel et al.			
	A06	4,462,806	07/1984	Mahoney et al.			
	A07	4,762,975	08/1988	Mahoney et al.			
	A08	4,835,383	05/1989	Mahoney et al.			
/MLP/	A09	4,896,035	01/1990	Mahoney et al.			
	A10						

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	B01							
	B02							
	B03							

**OTHER REFERENCES** (Including Author, Title, Date, Pertinent Pages, Etc.)

/MLP/	C01	Journal of Vacuum Science & Technology B, "Dry Surface Cleaning Using CO <sub>2</sub> Snow" by Sherman et al., July/august 1991, pp 1970-1977
	C02	Journal of Vacuum Science & Technology A, "Carbon Dioxide Jet Spray Cleaning of Molecular Contaminants" by Hills, Jan/Feb. 1995, pgs.30-34
	C03	Particulate Science and Technology, Vol. 6, Number 2, 1988, "Methods for Surface Particle Removal: A Comparative Study" by Bardina (no month)
/MLP/	C04	"Trends in Wafer Cleaning Technology" by Hattori, May 1995, Contamination Control, Wafer Cleaning 3rd page > half possibly pages 87 810 & 812
	C05	missing (?89?)

EXAMINER

/Marianne L. Padgett/

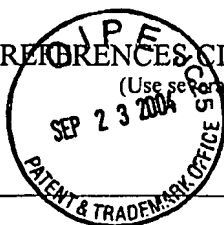
DATE CONSIDERED

10/29/2007

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

## LIST OF REFERENCES CITED BY APPLICANT

(Use separate sheets if necessary)



ATTY DOCKET NO.

060937-0179

APPLICATION NO

~~10/361,822~~

APPLICANT Robert Small

~~Brandon Shane SCOTT et al.~~

FILING DATE 3/18/2004

GROUP 1792

~~February 11, 2003~~~~1755~~

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/MLP/	A01	3,293,093	12/1966	Jones et al.			
	A02	4,769,073	09/1988	Tastu et al.			
	A03	4,959,113	07/1989	Roberts			
	A04	5,527,423	06/1996	Neville et al.			
	A05	5,354,490	09/1994	Finnigan			
	A06	5,445,996	08/1995	Kodera et al.			
	A07	5,773,364	06/1998	Farkas et al.			
	A08	5,783,489	07/1998	Kaufman et al.			
	A09	5,958,288	09/1999	Mueller et al.			
	A10	5,891,205	04/1999	Picardi et al.			
	A11	6,117,026	09/2000	Hayashi et al.			
	A12	6,117,783	09/2000	Small et al.			
	A13	6,156,661	12/2000	Small et al.			
	A14	6,235,693	05/2001	Cheng et al.			
	A15	6,248,704	06/2001	Cheng et al.			
	A16	6,251,150	06/2001	Small et al.			
	A17	6,313,039	11/2001	Small et al.			
	A18	6,435,947	08/2002	Mueller et al.			
/MLP/	A19	6,498,131	12/2002	Small et al.			
	A20						
	A21						

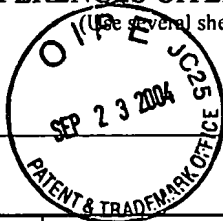
## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
	B01					
	B02					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

/MLP/	C01	"Mechanistic Aspects of Chemical mechanical Polishing of tungsten Using Ferric Ion Based Alumina Slurries" by Raghunath et al., ESP, Vol. 96-22, pp. 1-15 (no date-based on cites, 1996 or later)
/MLP/	C02	"Electrochemical Aspects of the Chemical Mechanical Planarization of Tungsten" by Basak et al., ESP Vol. 96-22, pp. 137-148 (no date-based on citations, 1996 or later)

<b>LIST OF REFERENCES CITED BY APPLICANT</b> (Use several sheets if necessary)	ATTY DOCKET NO.	APPLICATION NO <u>10/361,822</u>
	APPLICANT <b>Robert Small</b> <del>Brandon Shane SCOTT et al.</del>	
	FILING DATE <u>February 11, 2003</u>	GROUP <u>3/18/2004</u> AU 1792



### U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/MLP/	A01	6,022,400	2/2000	Izumi et al.			
	A02	6,177,026	1/2001	Wang et al.			
	A03	6,251,150	6/2001	Small et al.			
	A04	6,435,947	08/2002	Mueller et al.			
	A05	5,302,356	04/1994	Shadman et al.			
	A06	6,468,428	10/2002	Nishii et al.			
	A07	6,461,227	10/2002	Fang			
	A08	6,375,545	04/2002	Yano et al.			
/MLP/	A09	2002/0017063	02/2002	Beitel et al.			

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